



# Power MOSFETS

## DATASHEET

**LM30300NAI3A**

N-Channel  
Enhancement Mode MOSFET

-  Leadpower-semiconductor Corp., Ltd
-  sales@leadpower-semi.com
-  (03) 6577339 FAX : (03) 6577229
-  [www.leadpower-semi.com](http://www.leadpower-semi.com)



Quality Management Systems  
ISO 9001:2015 Certificate

## N-Channel Enhancement Mode MOSFET

### Pin Description

SOT-23 (TOP view)	Symbol	Product Summary												
		<table border="1"> <thead> <tr> <th>Symbol</th> <th>N-Channel</th> <th>Unit</th> </tr> </thead> <tbody> <tr> <td><math>V_{DSS}</math></td> <td>30</td> <td>V</td> </tr> <tr> <td><math>R_{DS(ON)-Max}</math></td> <td>24</td> <td><math>m\Omega</math></td> </tr> <tr> <td>ID</td> <td>5.4</td> <td>A</td> </tr> </tbody> </table>	Symbol	N-Channel	Unit	$V_{DSS}$	30	V	$R_{DS(ON)-Max}$	24	$m\Omega$	ID	5.4	A
Symbol	N-Channel	Unit												
$V_{DSS}$	30	V												
$R_{DS(ON)-Max}$	24	$m\Omega$												
ID	5.4	A												

### Feature

- Simple drive requirement
- Reliable and Rugged
- ROHS Compliant & Halogen-Free

### Applications

- Portable Equipment
- Battery Powered System

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30300NAI3A	SOT-23	Tape & Reel	3000 / Tape & Reel	15□□□

Note : □□□= Lot Code

### Absolute Maximum Ratings ( $T_J=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter		N-Channel	Unit
$V_{DSS}$	Drain-Source Voltage	30		V
$V_{GSS}$				
$T_J$	Maximum Junction Temperature	150		$^\circ C$
$T_{STG}$	Storage Temperature Range	-55 to 150		$^\circ C$
$I_{DM}^{(1)}$	Pulse Drain Current Tested	$T_A=25^\circ C$	11.2	A
$I_D$	Continuous Drain Current	$T_A=25^\circ C$	5.4	A
		$T_A=70^\circ C$	4.3	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ C$	1.1	W
		$T_A=70^\circ C$	0.7	
$I_{AS}^{(2)}$	Avalanche Current, Single pulse	$L=0.1mH$	11	A
$E_{AS}^{(2)}$	Avalanche Energy, Single pulse	$L=0.1mH$	6	$mJ$

### Thermal Characteristics

Symbol	Parameter		Rating	Unit
$R_{θJA}^{(3)}$	Thermal Resistance-Junction to Ambient	Steady State	110	$^\circ C/W$

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature  $150^\circ C$

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz.

N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_{DS}=250\mu\text{A}$	30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$	-	-	1	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu\text{A}$	1	1.5	2	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	-	-	$\pm 100$	$\text{nA}$
$R_{DS(\text{ON})}^{\text{(4)}}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}, I_{DS}=5.8\text{A}$	-	20	24	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_{DS}=5\text{A}$	-	24	31	
$g_{fs}$	Forward Transconductance	$V_{DS}=3\text{V}, I_{DS}=3\text{A}$	-	8.6	-	S
<b>Dynamic Characteristics <sup>(5)</sup></b>						
$R_G$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V},$ $\text{Freq.}=1\text{MHz}$	-	3.3	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V},$ $V_{DS}=15\text{V},$ $\text{Freq.}=1\text{MHz}$	-	500	-	$\text{pF}$
$C_{oss}$	Output Capacitance		-	62	-	
$C_{rss}$	Reverse Transfer Capacitance		-	53	-	
$t_{d(\text{ON})}$	Turn-on Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V},$ $I_D=1\text{A}, R_{\text{GEN}}=6\Omega$	-	3.1	-	$\text{nS}$
$t_r$	Turn-on Rise Time		-	21	-	
$t_{d(\text{OFF})}$	Turn-off Delay Time		-	25	-	
$t_f$	Turn-off Fall Time		-	18	-	
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}$ $I_D=10\text{A}$	-	8.4	-	$\text{nC}$
$Q_g$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V},$ $I_D=10\text{A}$	-	15	-	
$Q_{gs}$	Gate-Source Charge		-	1.2	-	
$Q_{gd}$	Gate-Drain Charge		-	4.6	-	
<b>Source-Drain Characteristics</b>						
$V_{SD}^{\text{(4)}}$	Diode Forward Voltage	$I_{SD}=1\text{A}, V_{GS}=0\text{V}$	-	0.8	1.1	V
$t_{rr}$	Reverse Recovery Time	$I_F=1\text{A}, V_R=15\text{V}$	-	1.3	-	$\text{nS}$
$Q_{rr}$	Reverse Recovery Charge		-	4.9	-	$\text{nC}$

Note <sup>(4)</sup> : Pulse test (pulse width $\leq 300\text{us}$ , duty cycle $\leq 2\%$ ).Note <sup>(5)</sup> : Guaranteed by design, not subject to production testing.

## N-Channel Typical Characteristics

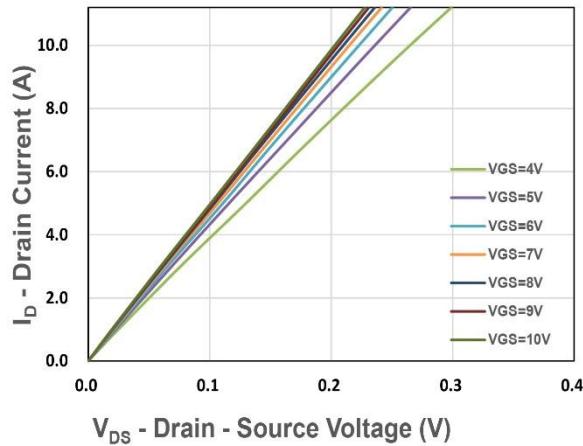


Figure 1. Output Characteristics

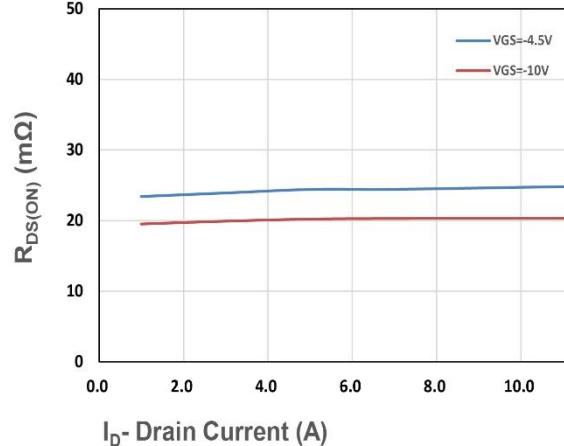


Figure 2. On-Resistance vs. ID

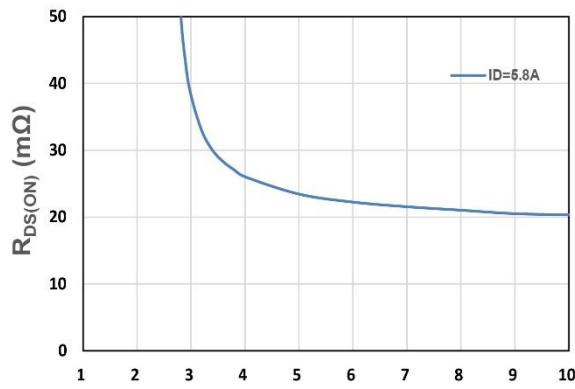


Figure 3. On-Resistance vs. VGS

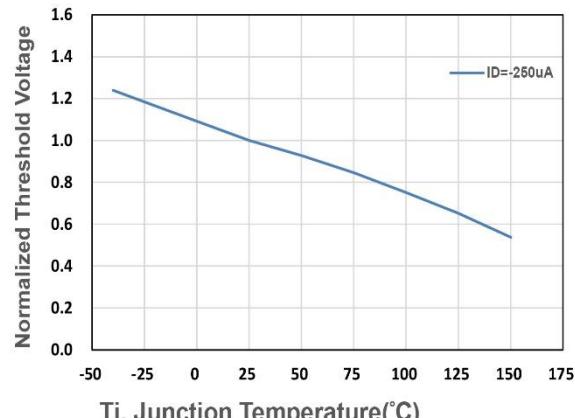


Figure 4. Gate Threshold Voltage

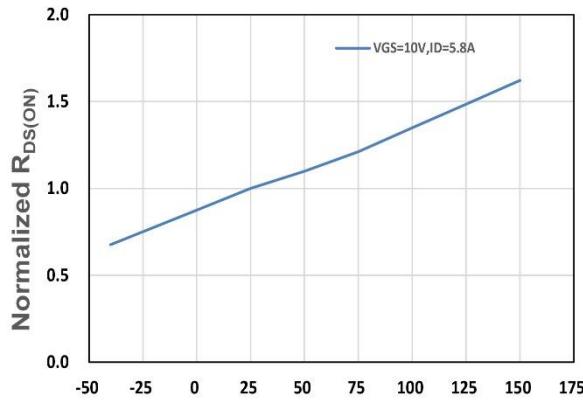


Figure 5. Drain-Source On Resistance

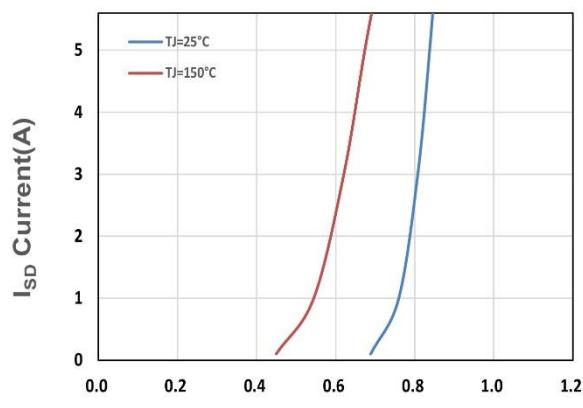
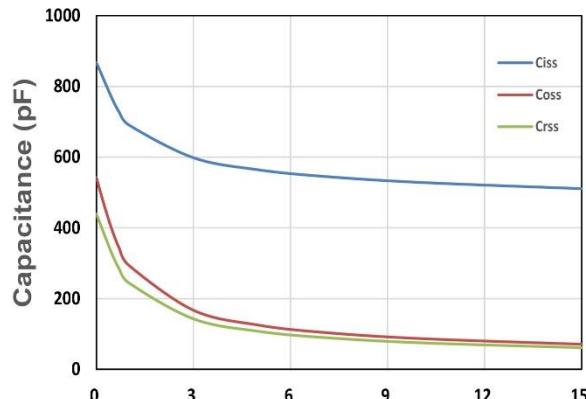
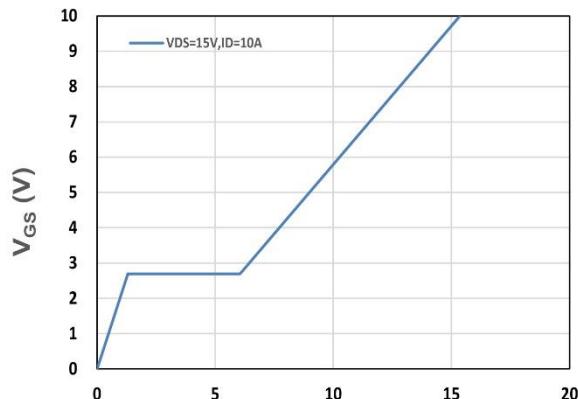


Figure 6. Source-Drain Diode Forward

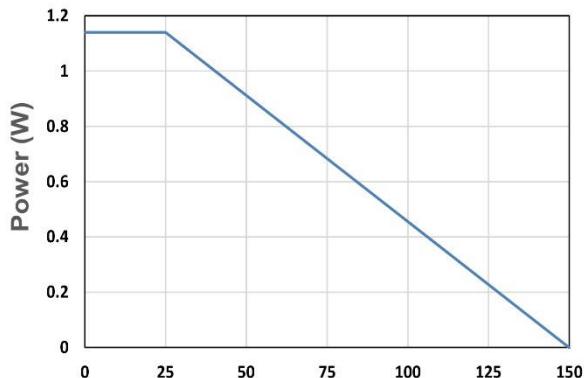
# LM30300NAI3A



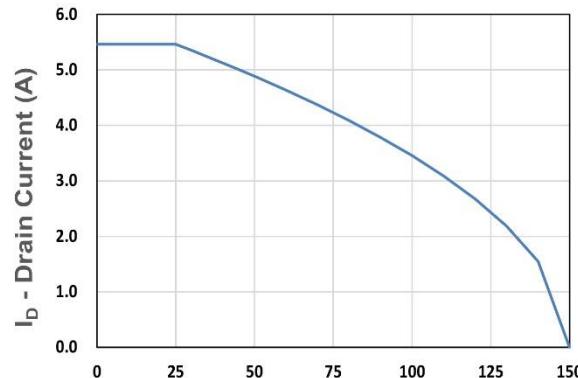
V<sub>DS</sub> - Drain - Source Voltage (V)  
Figure 7. Capacitance



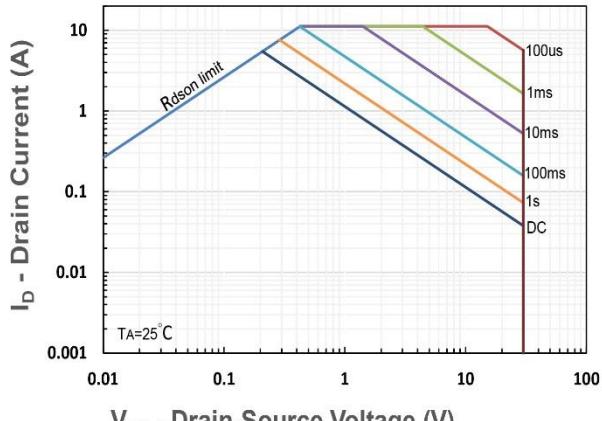
Q<sub>g</sub>, Total Gate Charge (nC)  
Figure 8. Gate Charge Characteristics



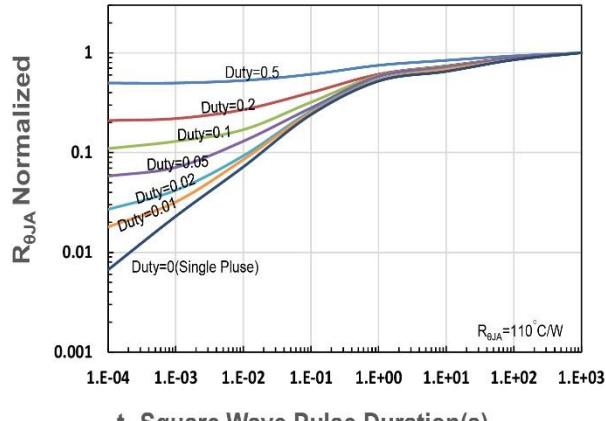
T<sub>A</sub> - Ambient Temperature (°C)  
Figure 9. Power Dissipation



T<sub>A</sub> - Ambient Temperature(°C)  
Figure 10. Drain Current



V<sub>DS</sub> - Drain-Source Voltage (V)  
Figure 11. Safe Operating Area



R<sub>qJA</sub> Normalized  
t<sub>1</sub>,Square Wave Pulse Duration(s)  
Figure 12. R<sub>qJA</sub> Transient Thermal Impedance